

Application/Control No.	Applicant(s)/Patent under Reexamination
10/809,399	YAMAKAWA ET AL.
Examiner	Art Unit

3661

Dalena Tran

SEARCHED.					
Class	Subclass	Date	Examiner		
101	25 37 39				
702	45,46				
	183 184 185				
700	21,79	piz/1/06	70		
7 4	25 37				
	39				
	46				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	11/29/06	DL	